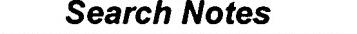


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/669,609	TANAKA, KEISUKE
	Examiner	Art Unit
	Yixing Qin	2625

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner